

**FAXED****IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicants: KOMURA et al.

Serial No.: 09/616,372

Filed: 7/13/2000

Title: METHOD FOR MEASURING
THICKNESS OF OXIDE FILM

Atty. Dkt.: 01-50

Art Unit: 2881

Examiner: Souw

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Date: 6 January 2005

CERTIFICATE OF FACSIMILE TRANSMISSIONI hereby certify that this correspondence is being facsimile transmitted to the USPTO (Fax. No. 703-872-9306) on this date: 6 January 2005
Typed Name: James E. Barlow.Signature: **REQUEST FOR INITIALED FORM PTO-1449**

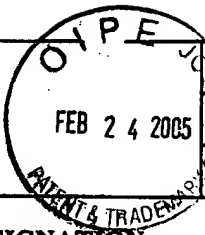
Sir:

In numbered paragraph 6 of the final office action dated 5 December 2003, the objection to the PTO-1449 filed on 13 July 2000 was withdrawn. However, the applicants did not receive an initialed copy of that PTO-1449.

The applicants respectfully request that an initialed copy of this PTO-1449 be returned at the earliest opportunity. A new copy of that PTO-1449 is attached to this paper for the examiner's convenience. Since this is merely a convenience copy of an earlier submitted PTO-1449, no IDS fee is required. However, please charge any unforeseen fees that may be due to Deposit Account No. 50-1147.

Respectfully submitted,

James E. Barlow
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ATTY. DKT NO. 1-50

09/616,372

APPLICANT KOMURA et al.

FILING DATE July 13, 2000

GROUP

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS

FOREIGN PATENT DOCUMENTS

TRANSLATION

		DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

		Institute of Electricity Communicational Education, "University Course of Electricity Institute", Electronic Material Engineering" Pgs. 228-231, March 5, 1982
		S. Kanbara and H. Fujiwara, "Applied Physics Selection, 3. Thin Film", Pgs. 200 - 203, June 5, 1979.
EXAMINER		DATE CONSIDERED